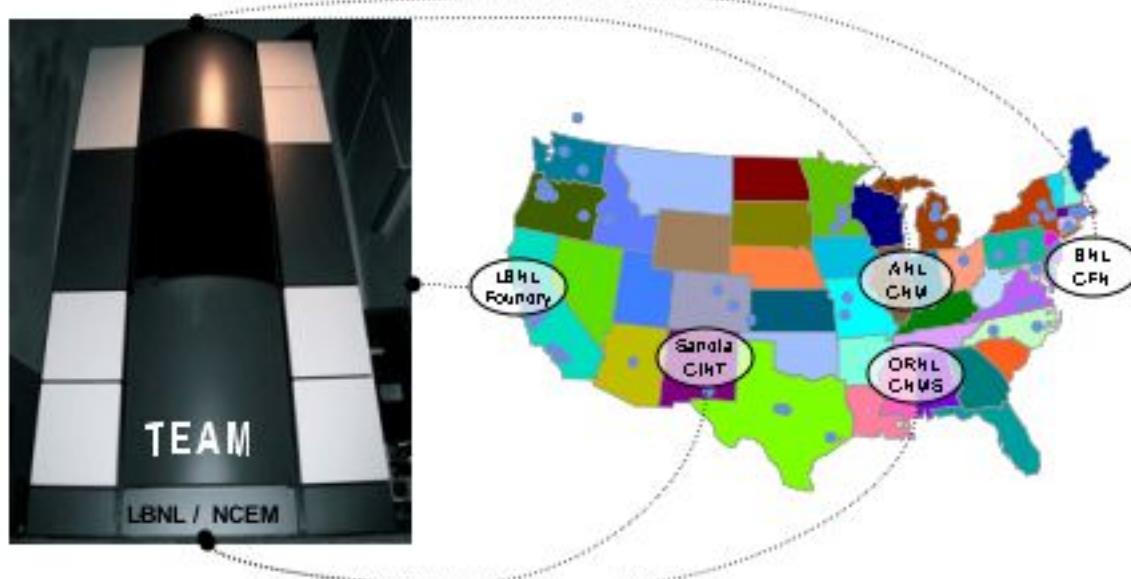


Extending the TEAM Control Room

Workshop on Remote Access to the Transmission Electron Aberration-corrected Microscope



the TEAM collaboration

*U. Dahmen,
P. Denes, A.M. Minor, C.
Kisielowski, B. Freitag, M.
Bischoff, H. van Lin, S.
Lazar, G. Knippels, P.
Tiemeijer, M. van der Stam,
S. von Harrach, M.
Stekelenburg, M. Haider, S.
Uhlemann, H. Müller, P.
Hartel, B. Kabius, D. Miller, I.
Petrov, E. A. Olson, T.
Donchev, E.A. Kenik, A.
Lupini, J. Bentley, S.
Pennycook, I.M. Anderson,
A.K. Schmid, T. Duden, V.
Radmilovic, Q. Ramasse, M.
Watanabe, R. Erni, E.A.
Stach*

- Background and overview
- Scientific needs at Nanoscience Centers
- TEAM operation - local and remote
- Broadband connection



Workshop Goals and Outline

N C E M

TEAM is important for nanoscience research facilities.

- Can we provide remote access for NSRC users?
Establish access portals at 5 nanoscience centers.
Workshop structure
- Limiting factors
 - Bandwidth (ESnet)
 - Security (National Labs)
 - Infrastructure (NSRCs)*What is TEAM
Background + Overview*
- Scientific needs
 - Discuss scientific opportunities
 - Establish modes of operation*Scientific needs and
capabilities at NSRCs and
partner labs*
- Types of experiment
 - Follow-up to on-site visit (familiarity with instrument essential)
 - Data-taking (image sequence, TFS, kinetics, standard tomography, spectrum imaging,...)*Instrument operation,
software, stages and
support*
- Logistics (proposal process, scheduling, local support,...)
- Mechanics (control interface, protocols,...)
*Remote operations
Networks, data transfer
Howto make it real*

8:30 am	<i>Welcome, TEAM overview and workshop goals.....</i>	Uli Dahmen
8:55 am	<i>TEAM project status</i>	Peter Denes
9:20 am	<i>CNMS overview and needs for advanced microscopy.....</i>	Linda Horton
9:45 am COFFEE		
10:15 am	<i>Foundry overview and needs for advanced microscopy.....</i>	Jim De Yoreo
10:40 am	<i>Electron microscopy and nano-science at ANL: new opportunities through TEAM</i>	Dean Miller
11:05 am	<i>In situ electron microscopy enabled by a TEM-SPM platform at CINT</i>	Jianyu Huang
11:30 am	<i>Overview and needs for electron microscopy at CFN</i>	Lihua Zhang
11:55 am	LUNCH	
1:00 pm	<i>The SHaRE user facility and microscopy at ORNL</i>	Karren More
1:25 pm	<i>TEAM stage: opportunities for in-situ microscopy.....</i>	Ivan Petrov
1:50 pm	<i>TEAM stage: prospects for remote operations</i>	Thomas Duden
2:15 pm	<i>Driving TEAM remotely: operations, alignments, feasibility</i>	Rolf Erni
2:40 pm	COFFEE and TEAM VISIT	
3:25 pm	<i>TEAM software</i>	Quentin Ramasse/Earl Cornell
3:45 pm	<i>ESNet.....</i>	Eli Dart
4:10 pm	<i>Practical aspects and requirements of remote microscopy operation for research oriented applications.....</i>	Masashi Watanabe
4:35 pm	<i>Remote microscopy at FEI.....</i>	Auke van Balen
5:00 pm	<i>Discussion</i>	Nestor Zaluzec

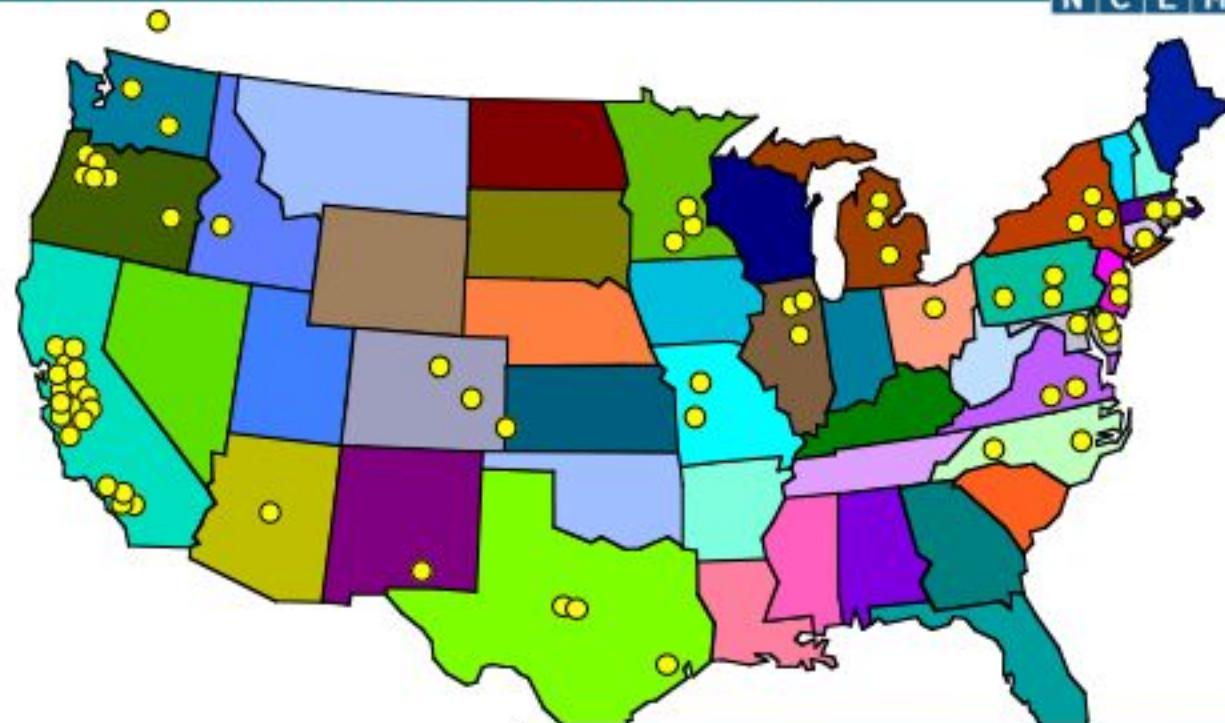


NCEM

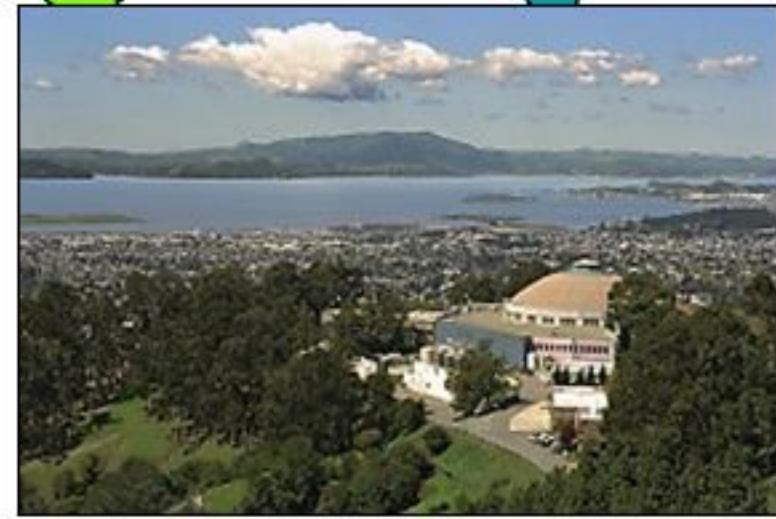
DOE user facility for electron microscopy

N C E M

- Free access controlled by external Proposal Review Committee



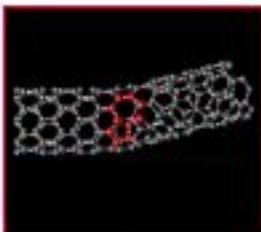
~250 users per year



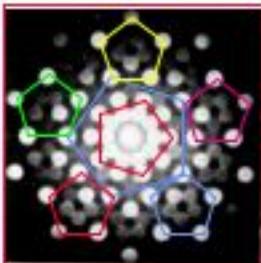
Electron Scattering

Significant achievements in materials science

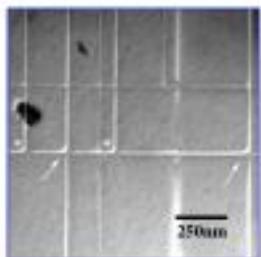
N C E M



- New materials
Nanotubes



- Phase transformations
Quasicrystals



- Defects
Strength of crystals

Electron microscopy is an integral part of the discovery and development of new materials.

50% of all materials research utilizes TEM.

Future opportunities such as

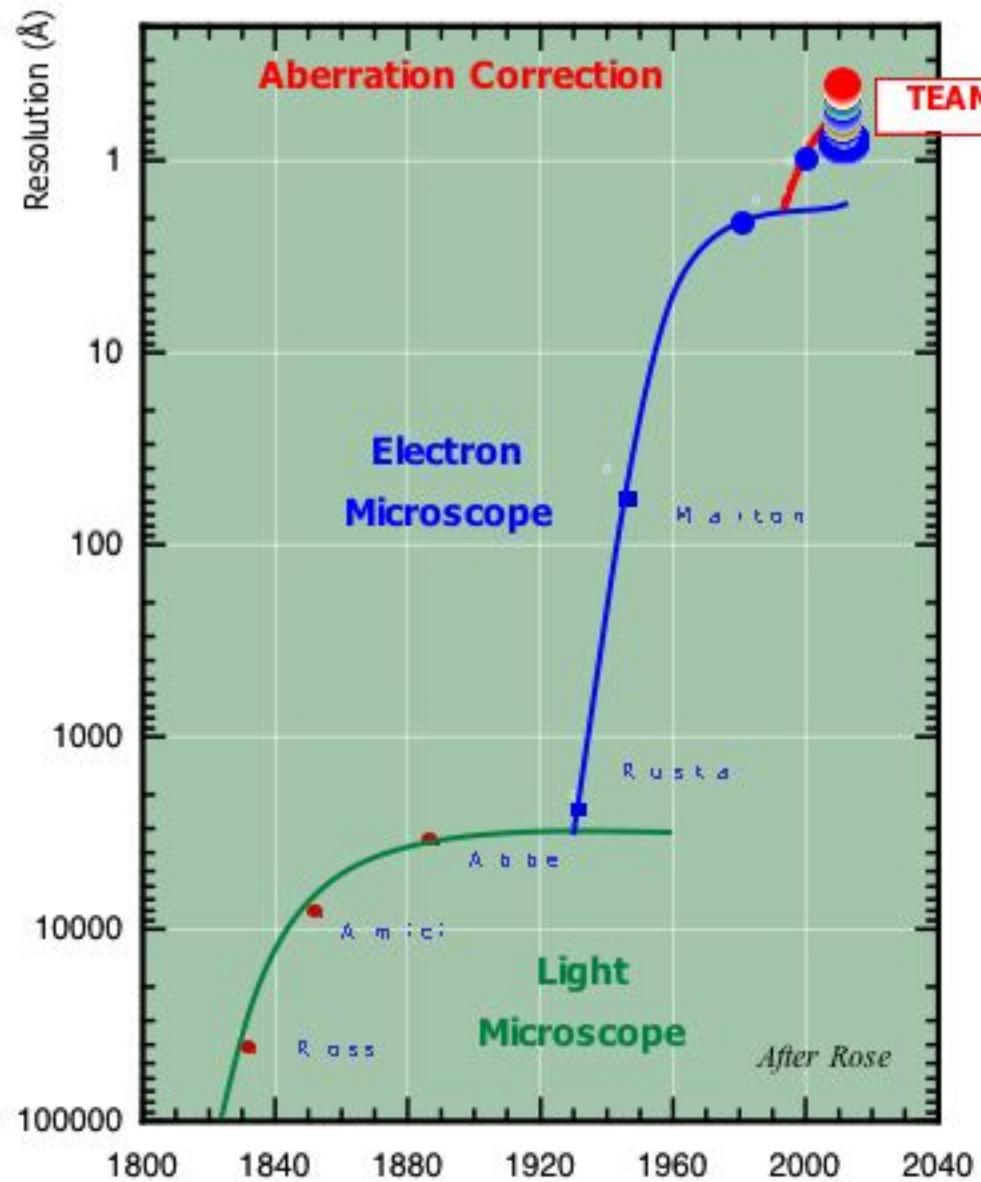
- 3D atomic resolution,
- in-situ probing of individual nanostructures,
- ultrafast dynamics,
- hard/soft matter composites....

However, instrument performance remains limited by lens aberrations...

Historical Perspective

Why now?

N C E M



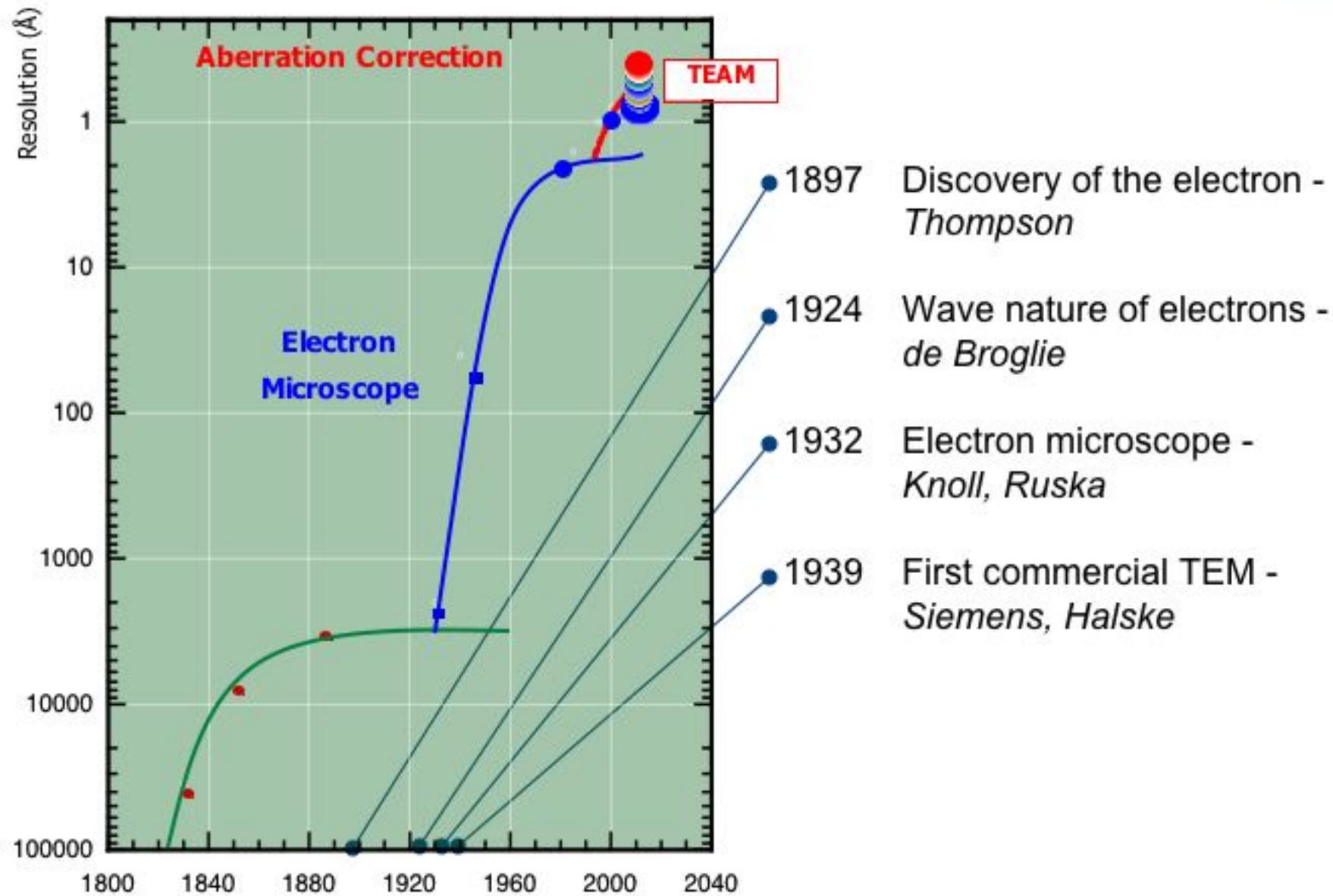
- A breakthrough in electron optics removes the barrier that has limited the performance of the electron microscope since its invention.
- Simultaneous advances in computers, electronics, detectors,...
- Nanoscience and technology centers need atomic-level characterization.
- Aberration correction key to nanomaterials research.



Historical Perspective

significant events

N C E M

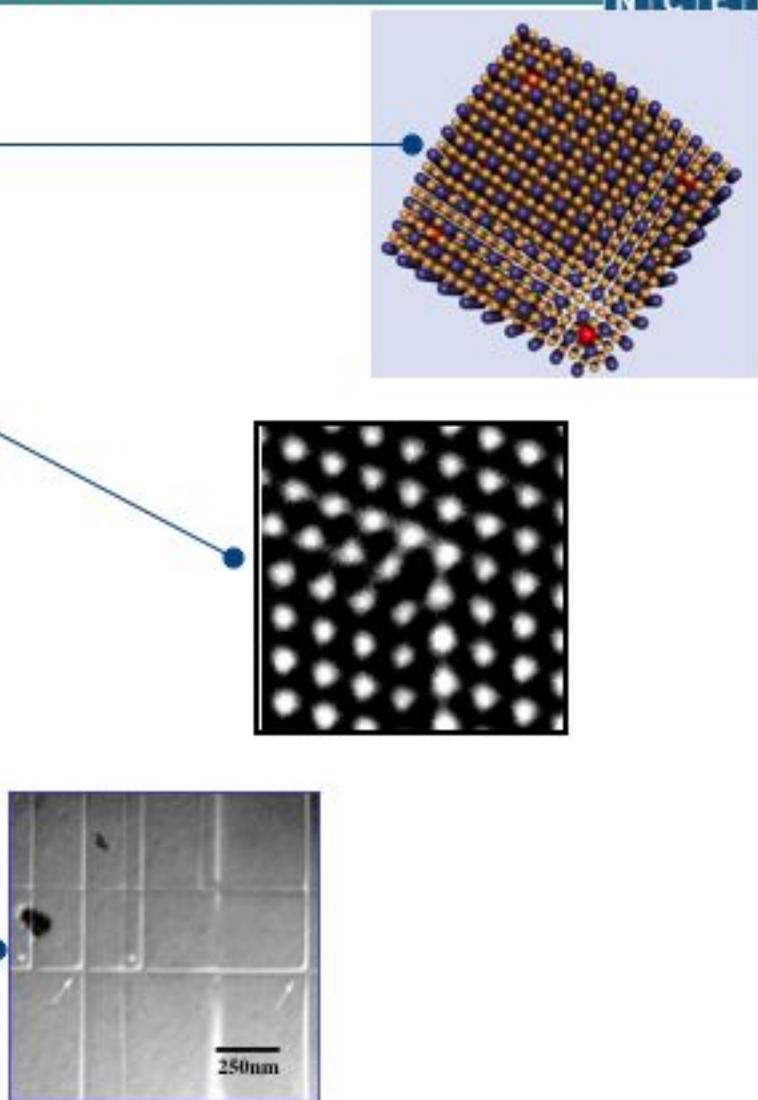
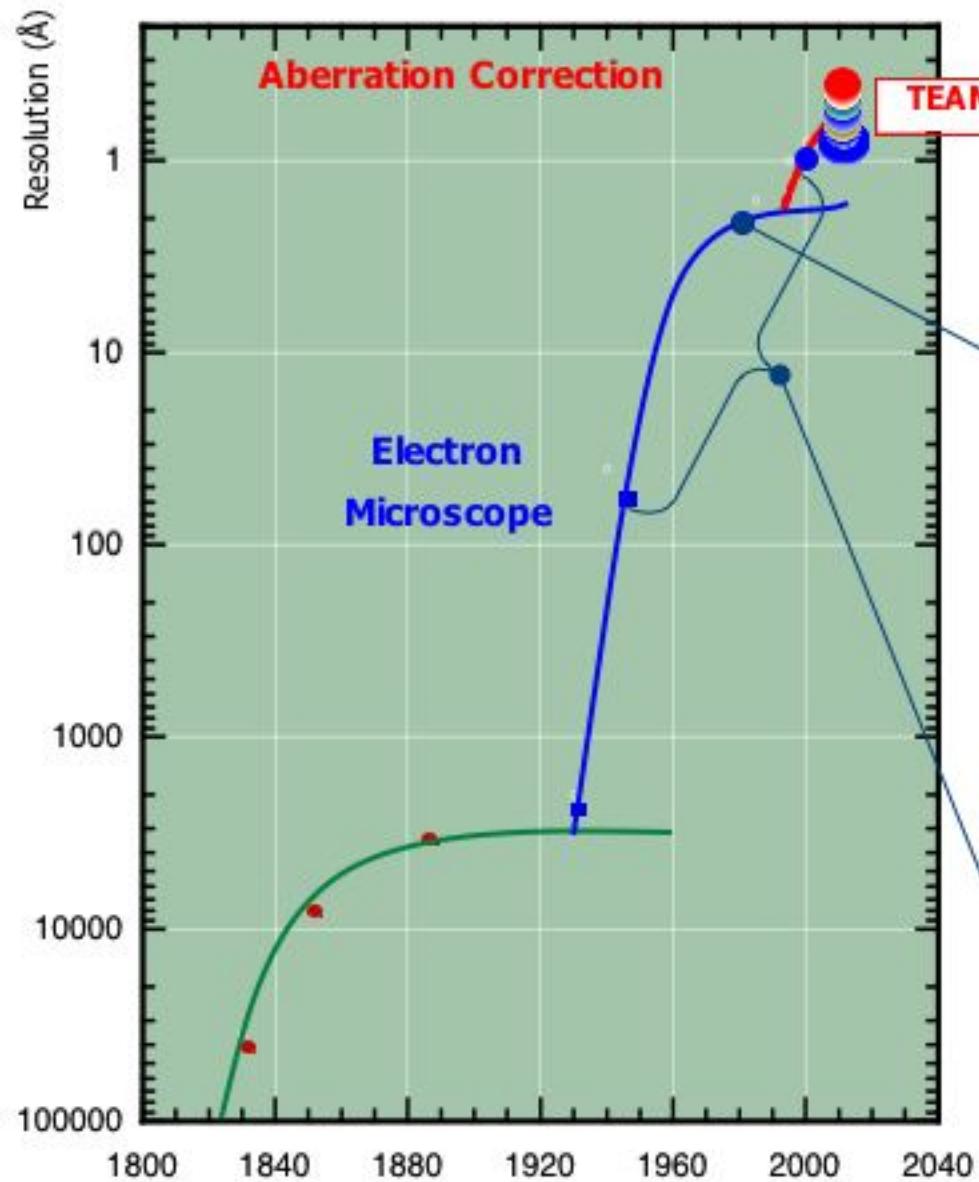




Historical Perspective

significant events

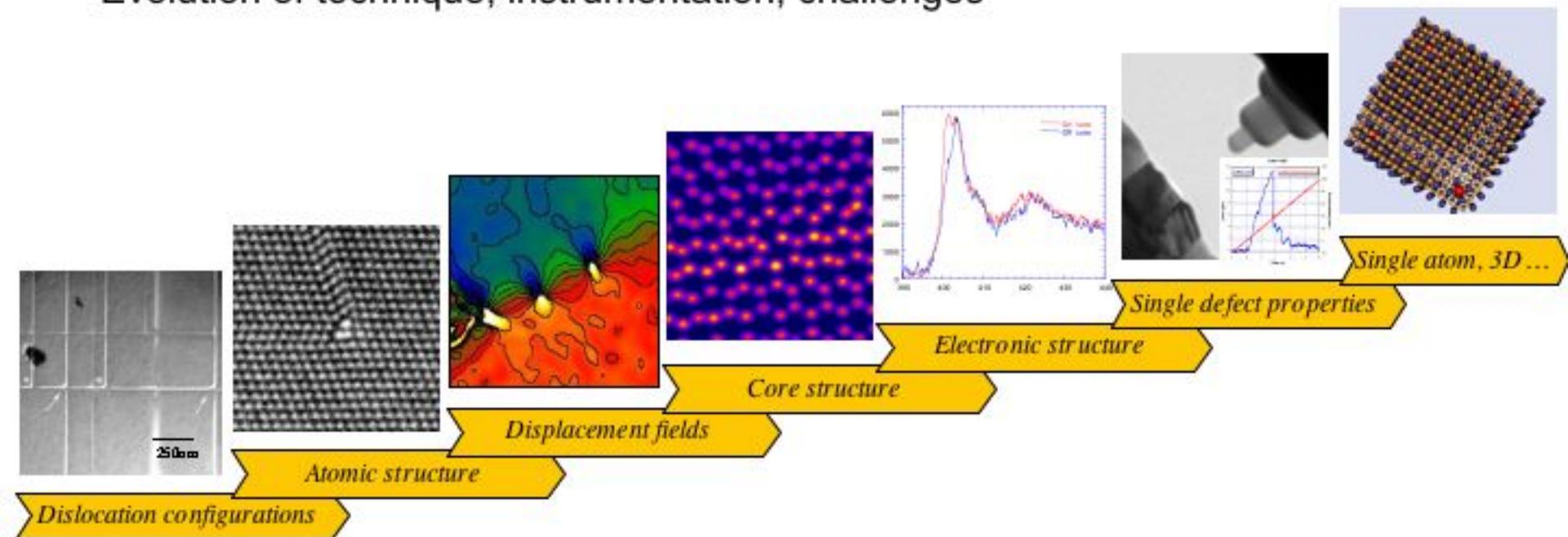
N C I E M



Defects in Materials

Recent history of TEM's growing role

Evolution of technique, instrumentation, challenges



Diffraction contrast

Atomic resolution

Computing

Z-contrast

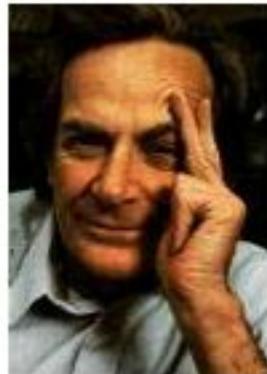
Spectroscopy

Dynamics

Aberration correction

Feynman's Challenge

"It would be very easy to make an analysis of any complicated chemical substance; all one would have to do would be to look at it and see where the atoms are. The only trouble is that the electron microscope is one hundred times too poor ... I put this out as a challenge: Is there no way to make the electron microscope more powerful?"



– *Richard P. Feynman, 1959,
"There's Plenty of Room at the Bottom"*



TEAM Project

Transmission Electron Aberration-corrected Microscope

N C E M

A collaborative project to develop the next-generation electron microscope.



Multiple partners, led by NCEM.
First instrument installed in Berkeley in December 2007.

Unprecedented scientific opportunities for observing the atomic-scale order,
electronic structure and dynamics of
individual nanostructures ...



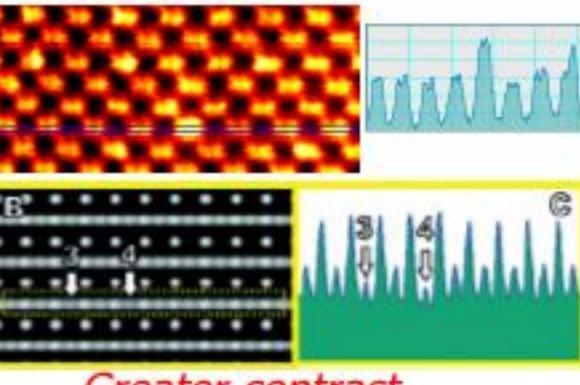
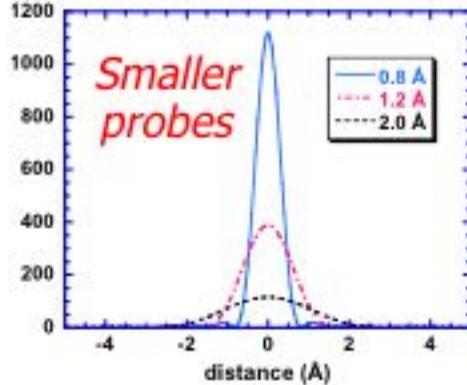
What Does Aberration Correction Buy?

NCEM

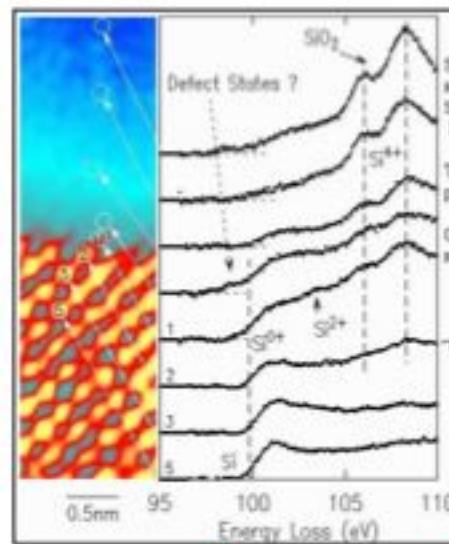
Conventional electron microscopes: $d \sim 100 \text{ \AA}$

C_s - corrected electron microscopes: $d \sim 40 \text{ \AA}$

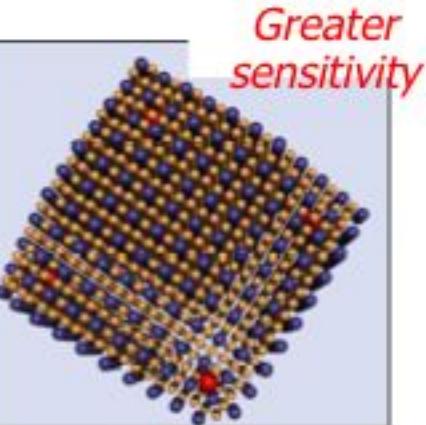
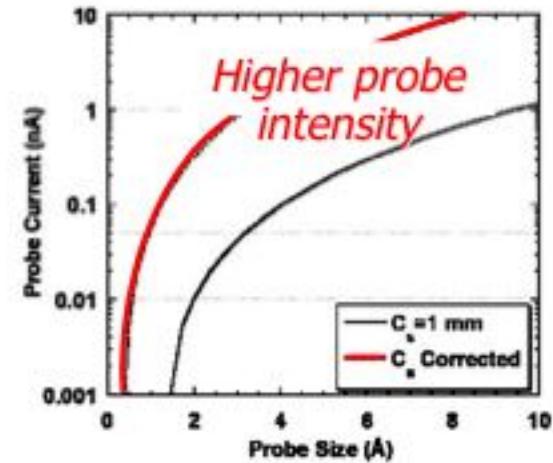
$C_s + C_c$ - corrected microscopes (TEAM): $d \sim 20 \text{ \AA}$



Greater contrast



More signal



Greater sensitivity



TEAM Background

Involvement of the scientific community



- 2000 Stringer BESAC Panel Review endorsement of TEAM "vision document"
 - 1st TEAM Workshop at ANL July 2000
 - 2nd TEAM Workshop at LBNL July 2002
 - 3rd TEAM workshop
 - MSA San Antonio, August 2003
 - 4th TEAM workshop / Focused Interest Group
 - MSA Savannah, August 2004
 - In-situ TEAM workshop,
 - FS-MRL, Illinois, July 2005
 - TEAM symposium
 - MSA Honolulu, August 2005
 - MSA 2006, 2007, AVS 2007, MRS 2007...
- Scientific Advisory Committee
 - C.B. Carter, U Minnesota
 - J.A. Eades, Lehigh
 - J. Silcox, Cornell
 - J.C.H. Spence, ASU
 - R. Tromp, IBM

<http://www.lbl.gov/LBL-Programs/TEAM/index.html>

WORKSHOP REPORT
ABERRATION CORRECTION IN ELECTRON MICROSCOPY
MATERIALS RESEARCH IN AN ABERRATION-FREE ENVIRONMENT

July 18-20, 2000

National Science Division
Argonne National Laboratory

REPORT
SECOND TEAM WORKSHOP

MATERIALS RESEARCH IN AN ABERRATION-FREE ENVIRONMENT

July 18 - 19, 2002

Lawrence Berkeley National Laboratory

Sponsored and Organized by

Electron Microscopy Center (EMC)
Argonne National Laboratory

National Center for Electron Microscopy (NCEM)
Lawrence Berkeley National Laboratory

Center for Microscopy and Microanalysis of Solid
Ferromagnetic Materials Research Laboratory

Shared Research Facilities Program (SRFP)
Oak Ridge National Laboratory

REPORT

SECOND TEAM WORKSHOP

MATERIALS RESEARCH IN AN ABERRATION-FREE ENVIRONMENT

July 18 - 19, 2002

Lawrence Berkeley National Laboratory

REPORT

Third TEAM Workshop

San Antonio, Texas August 8, 2003

Organized by

Electron Microscopy Center, Lawrence Berkeley National Laboratory

Hosted by

Argonne National Laboratory, Argonne, Illinois

Chair:

Tom H. Schaedler

Co-chair:

John D. Gaskins

Co-chair:

James A. Eades

Co-chair:

David A. Muller, Cornell University

Materials Research in an
Aberration-Free Environment

July 11 - August 1, 2004

Oglethorpe Auditorium, Georgia Institute of Technology
Atlanta, Georgia

2004 Focused
Interest Group

Materials Research in an
aberration-free environment

2004 Focused Interest Group Pre-Congress Meeting

Organized by

Georgia Institute of Technology, Atlanta, Georgia, United States

REPORT

Materials Research in an
Aberration-Free Environment

July 11-August 4, 2005

Bellwether Conference Center
Bioscapes, Brazil - USA

Organizer:

Georgia Institute of Technology, Atlanta, Georgia, United States

Chair:

John D. Gaskins

Co-chair:

James A. Eades

Co-chair:

David A. Muller, Cornell University

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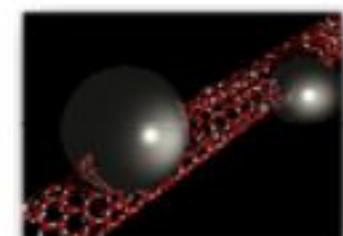
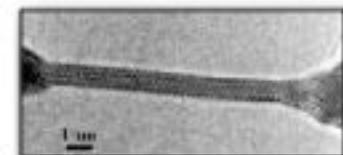
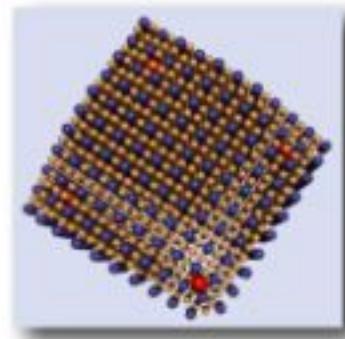


TEAM is Driven by Scientific Needs

N C E M

Extraordinary scientific opportunities by direct observation of individual nanostructures

- three-dimensional atomic-scale structure, shape, and defect distribution
- spectroscopic identification and location of individual dopant atoms
- direct imaging of the atomic-scale structure of glasses
- electronic structure of individual point defects
- non-spherical charge density and valence electron distribution
- in-situ synthesis of novel nanoscale structures
 - e.g., electron-beam lithographic removal of atomic columns
- in-situ observation of properties and response to external variables
 - temperature, stress, chemical activity, and applied electric and magnetic fields...

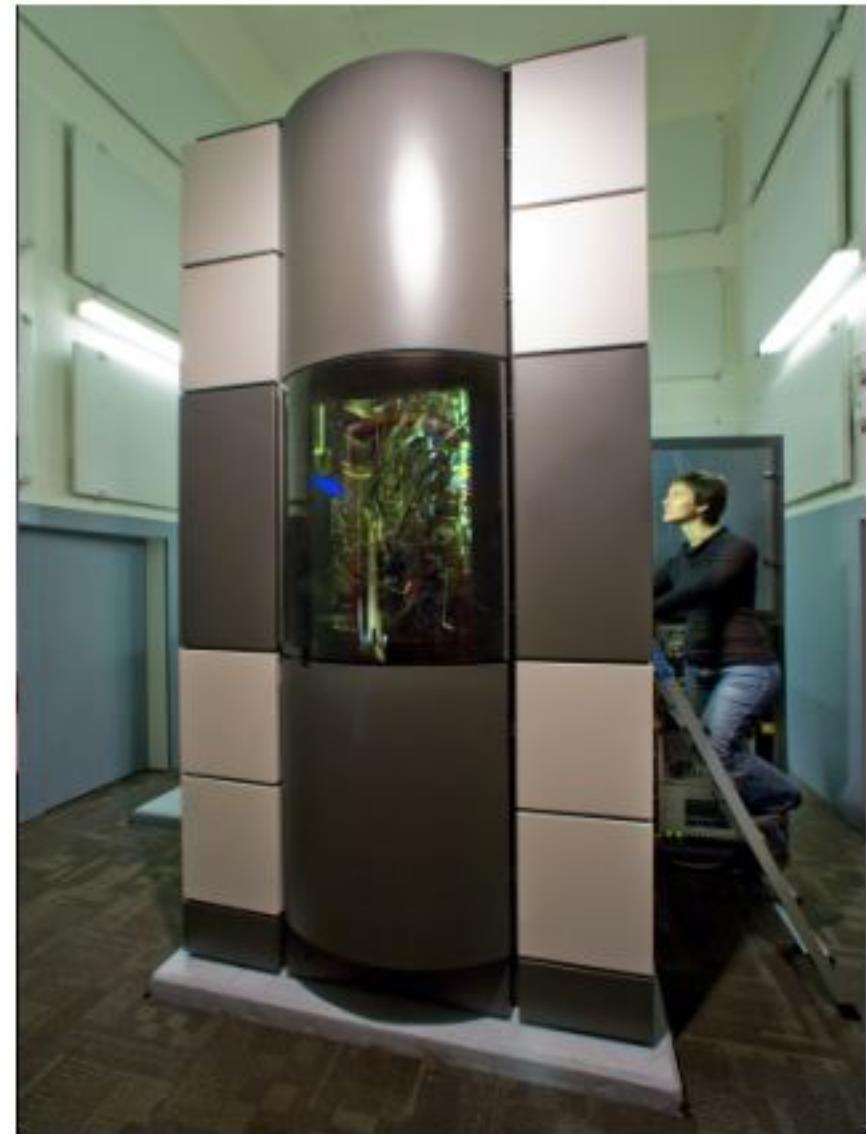
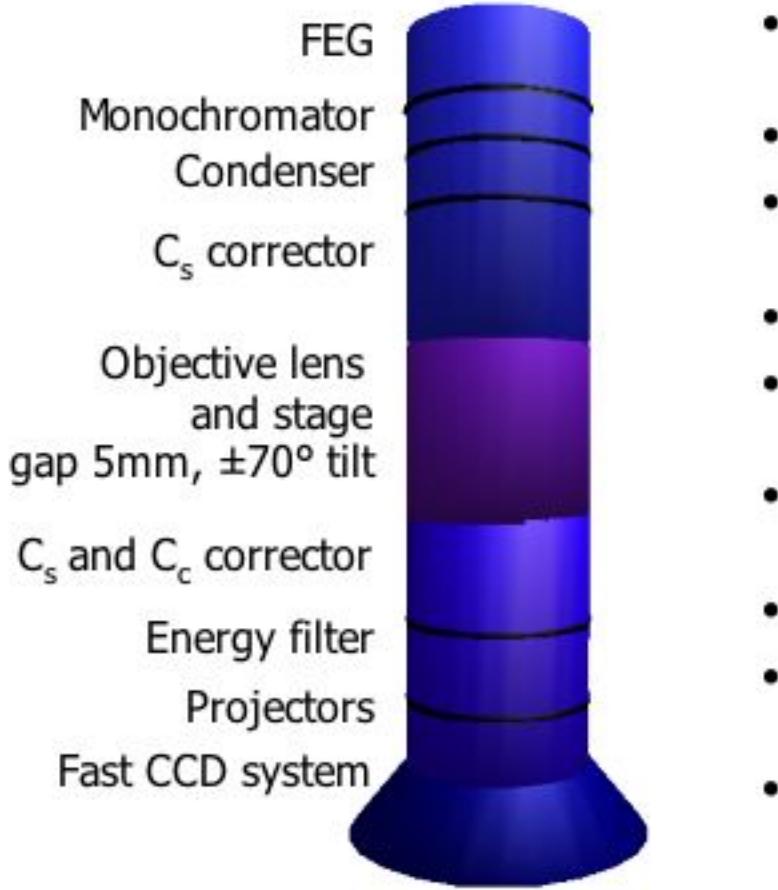


... all with unprecedented spatial, spectral & temporal resolution



The TEAM Instrument

N C E M



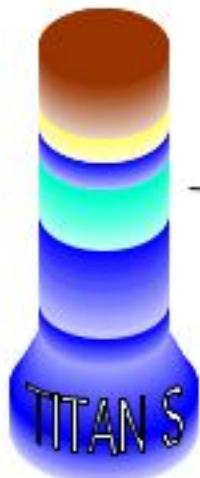


Parallel Technological Developments

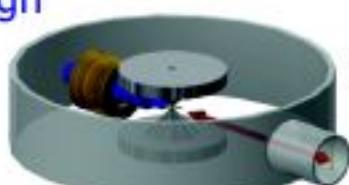
stepwise integration 2006-09

N C E M

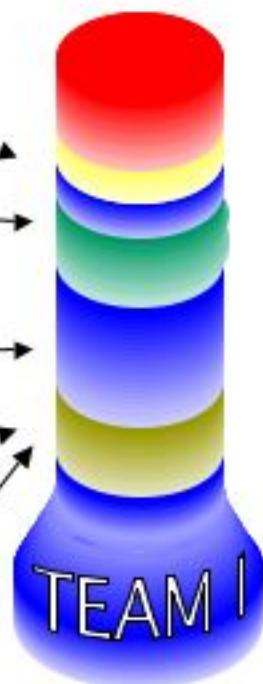
CEOS & ORNL:
STEM + C_s -correction



FEI:
Titan column,
High-brightness FEG,
sample exchange



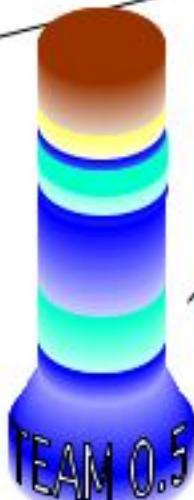
LBNL 2009



CEOS & ANL:
 C_c -correction



LBNL:
Double C_s -correction

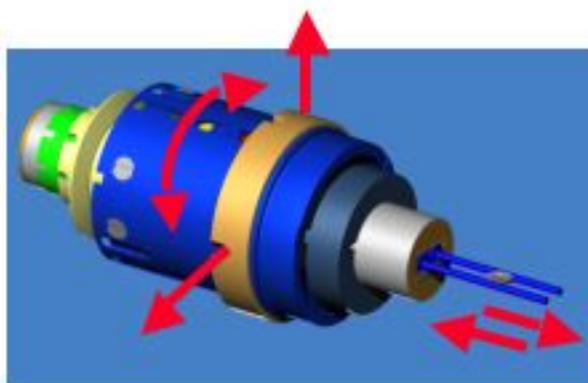


A. Schmid, T. Duden, NCEM + E. Olson I. Petrov, FS-MRL UIUC

- Design inspired by AFM
- Small, high stiffness, high resonance frequency
- Piezo-controllers
- No link to environment

Capacitive Position Sensing

- Absolute measurement
- No ‘homing’ necessary.
- Precision to a few nm



Enabling special experiments

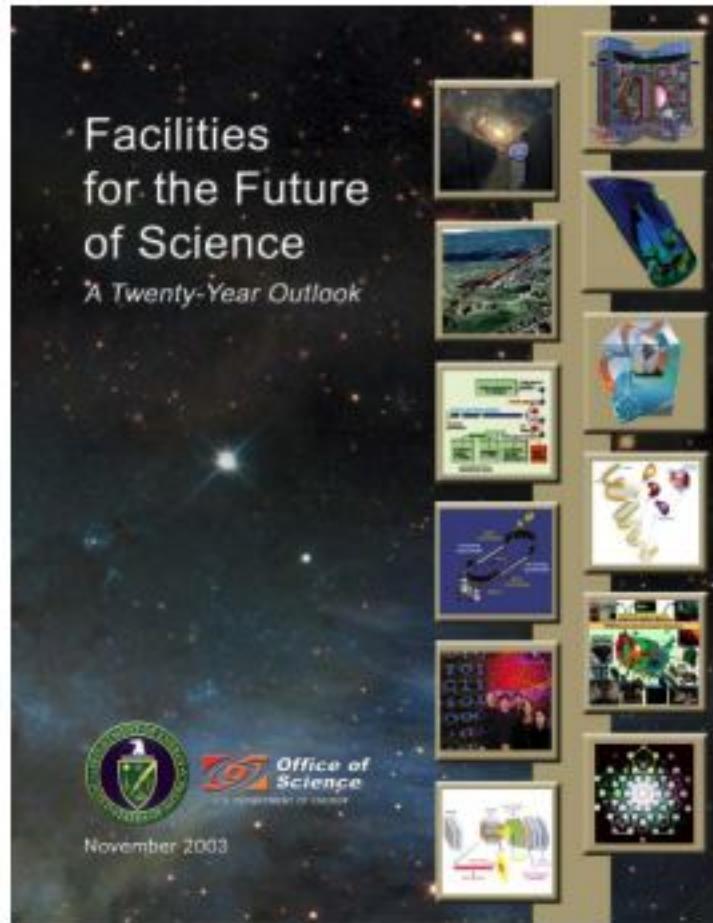
- Tomography
- Focal series
- Sample scan
- Spectroscopy
- Low-dose ...



TEAM on Track

a whistlestop on DOE's Roadmap for the Future of Science...

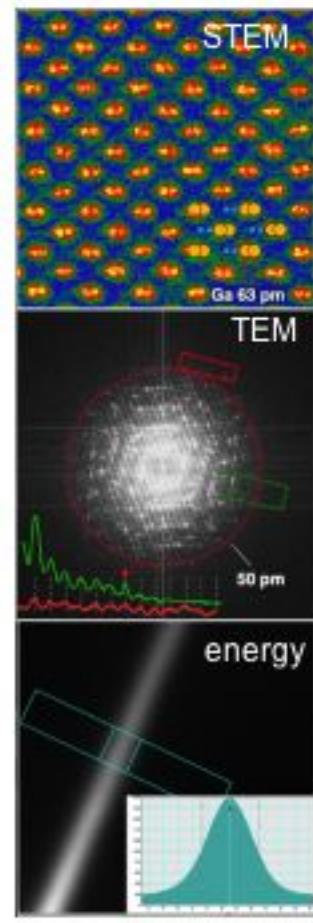
N C E M



TEAM is a small project but important in the big picture of DOE plans for the future of science.



TEAM 0.5 at NCEM



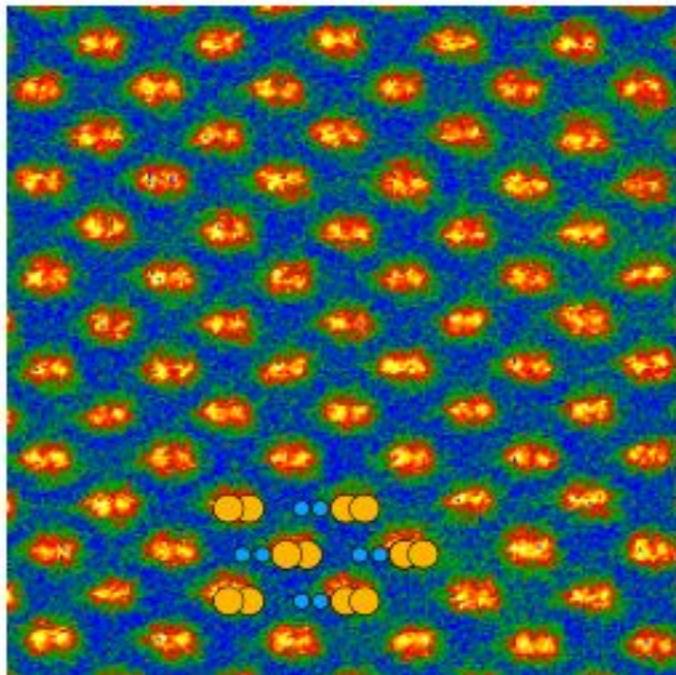
TEAM 0.5 has met its major milestones ahead of schedule -

- 0.5 Å information transfer in TEM and STEM,
- 0.1 eV energy spread.

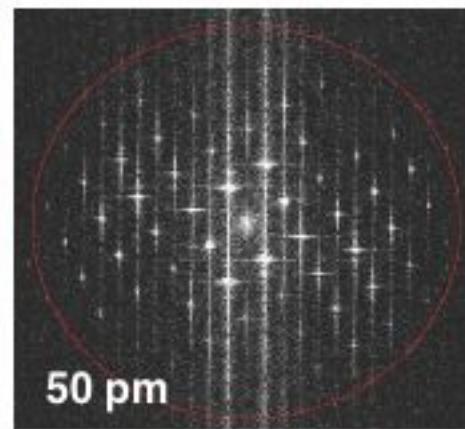
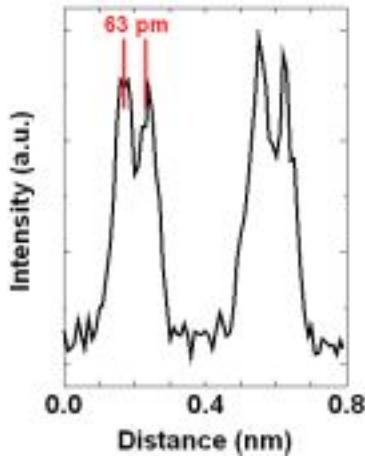


TEAM 0.5 Performance in STEM

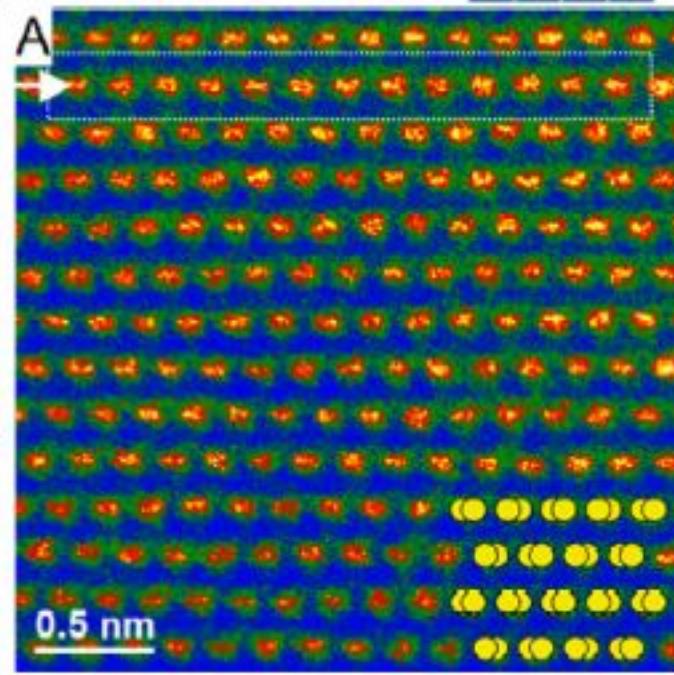
N C E M



GaN 112 63pm

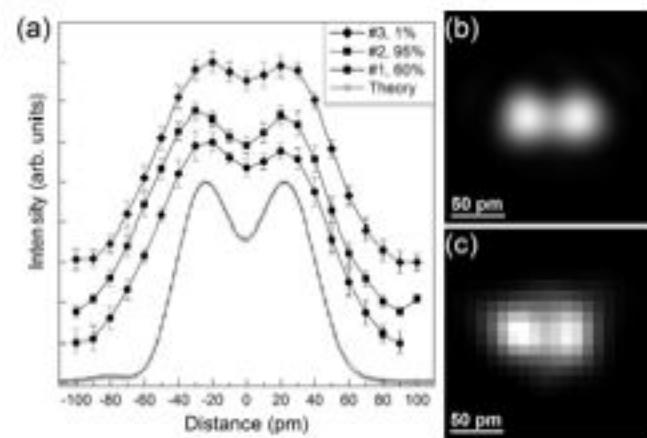


50 pm



Ge 114 47pm

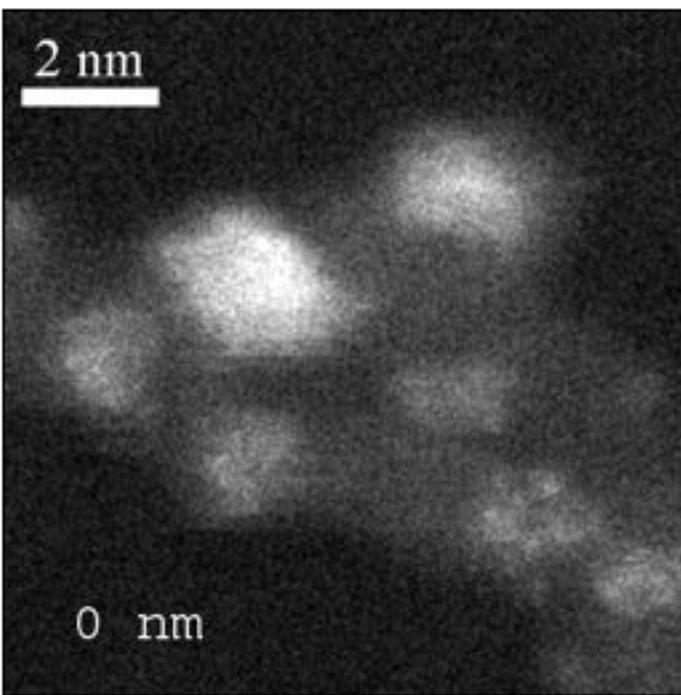
R. Erni



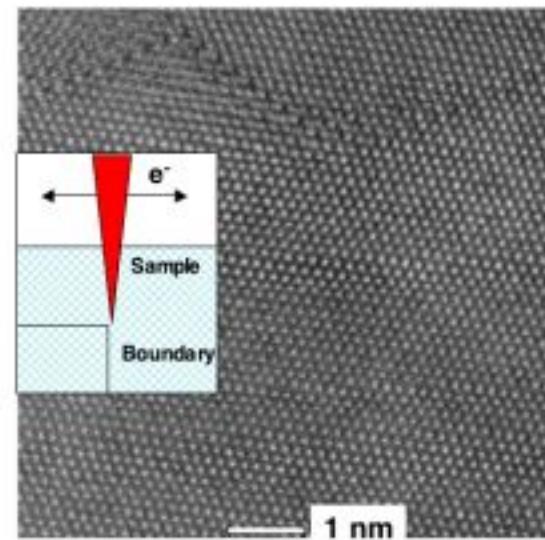
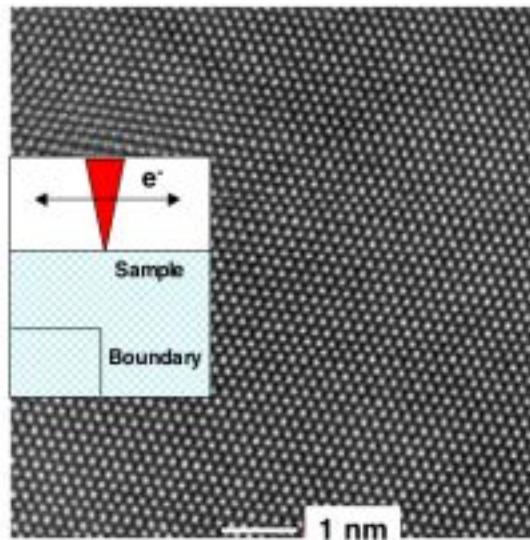
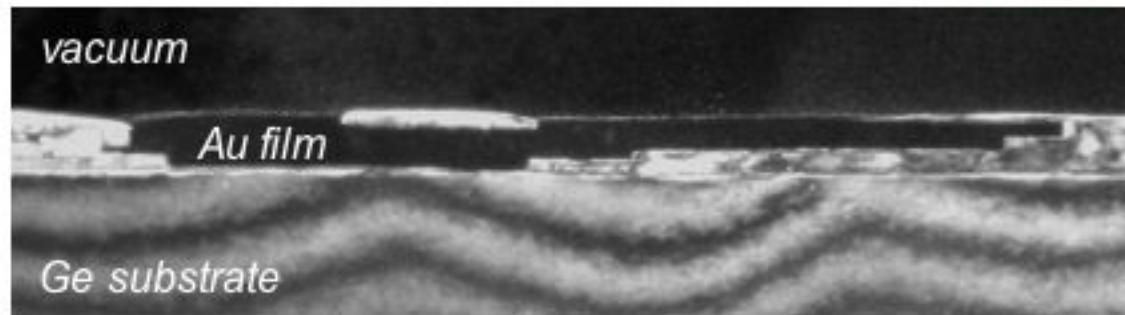
Depth Sectioning Tomography

Convergence angle reduces depth of focus

N C E M



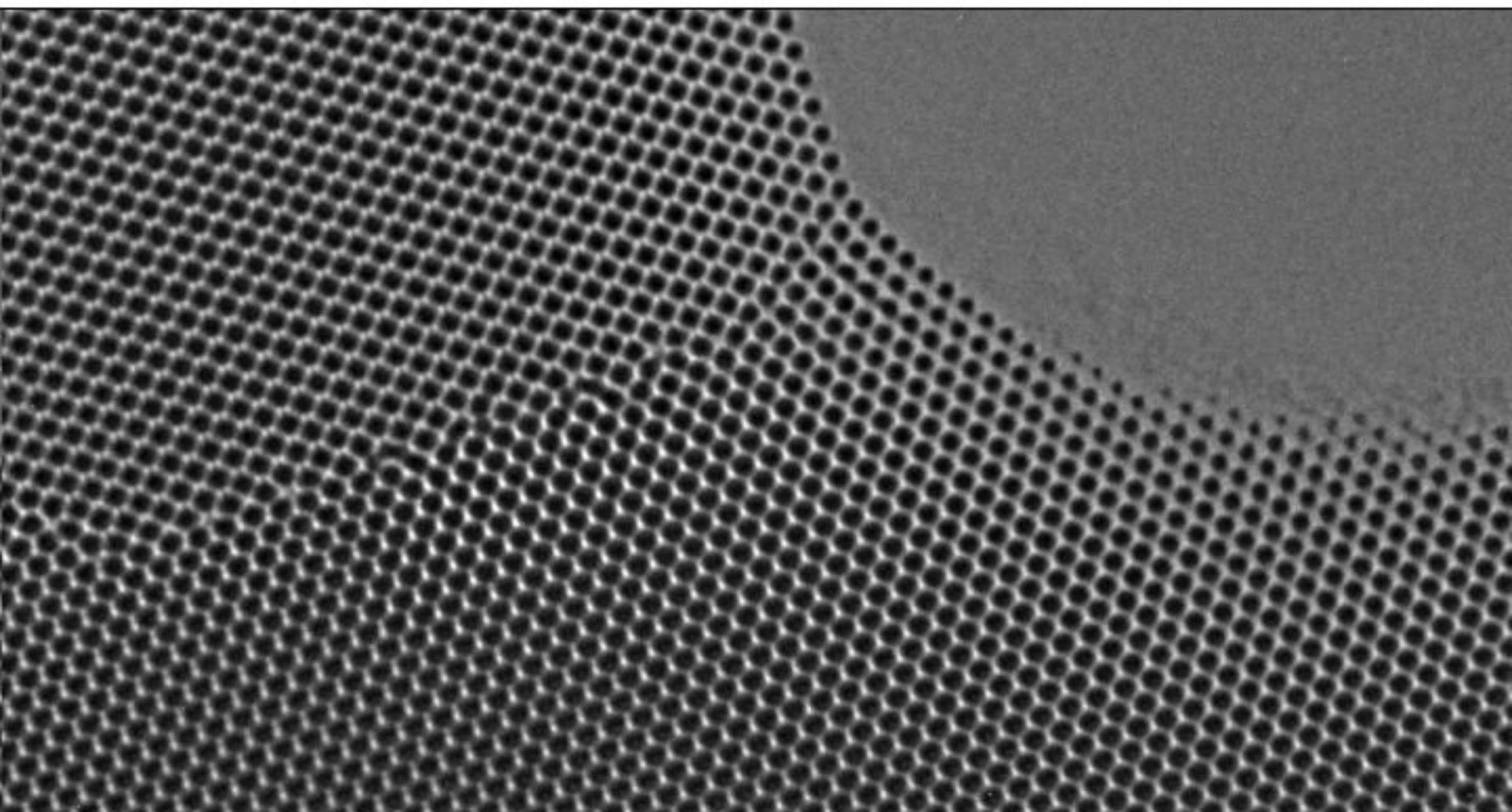
HAADF depth series of (Pt,
Ru) catalyst on $\gamma\text{-Al}_2\text{O}_3$.



Imaging a buried interface in Au bicrystal - TEAM 0.5

TEAM 0.5

atomic structure of $90^\circ <110>$ tilt boundary in Au



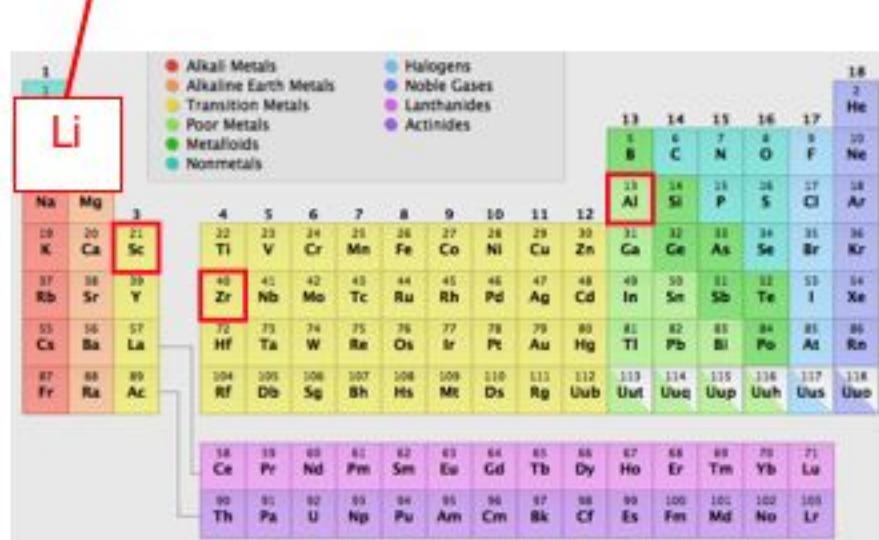
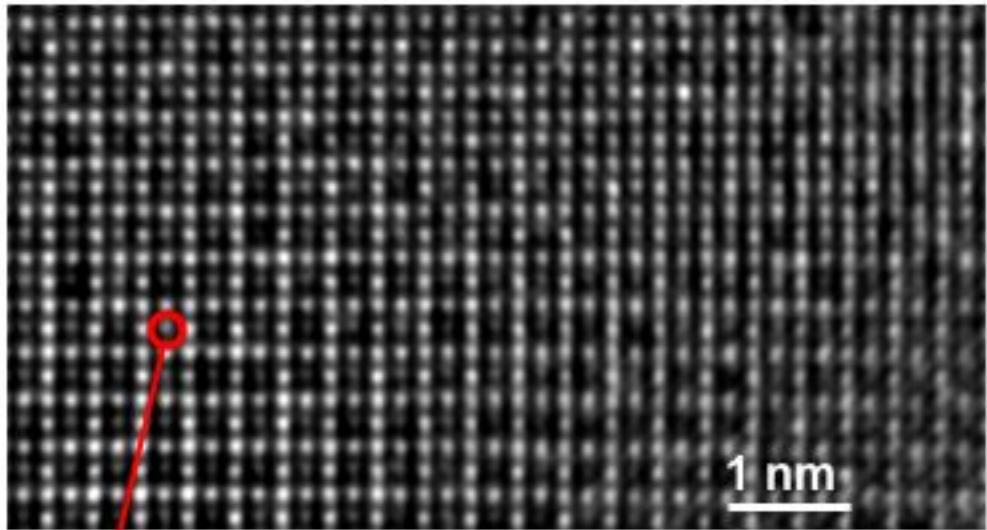


Resolving Li in Al-(Li,Sc,Zr) Alloy

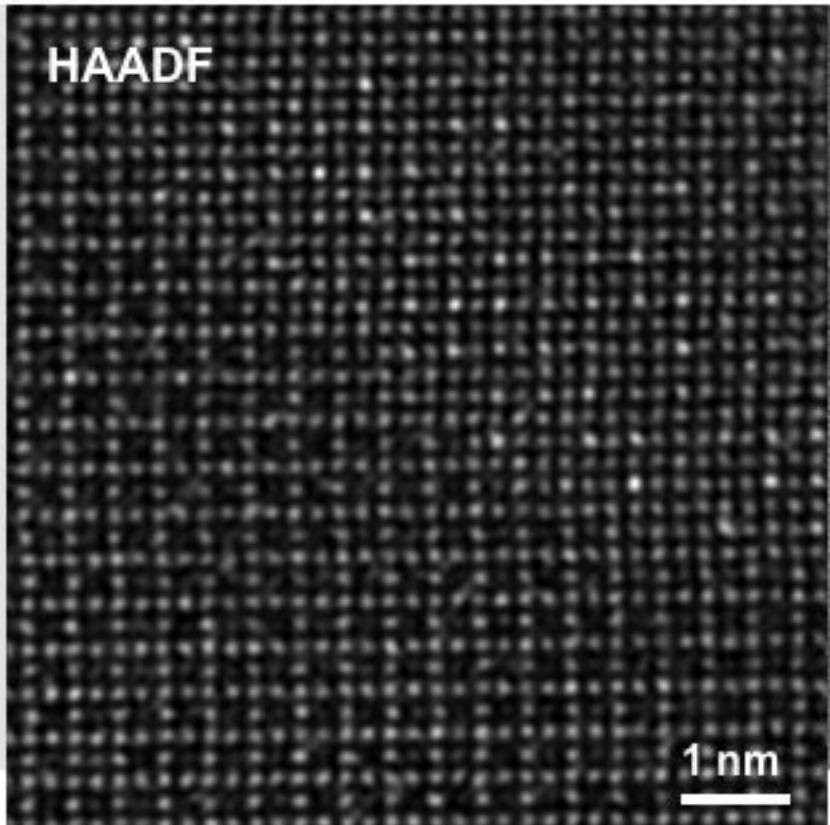
V. Radmilovic, M. Rossell, R. Erni

NCEM

TEM phase of exit wave

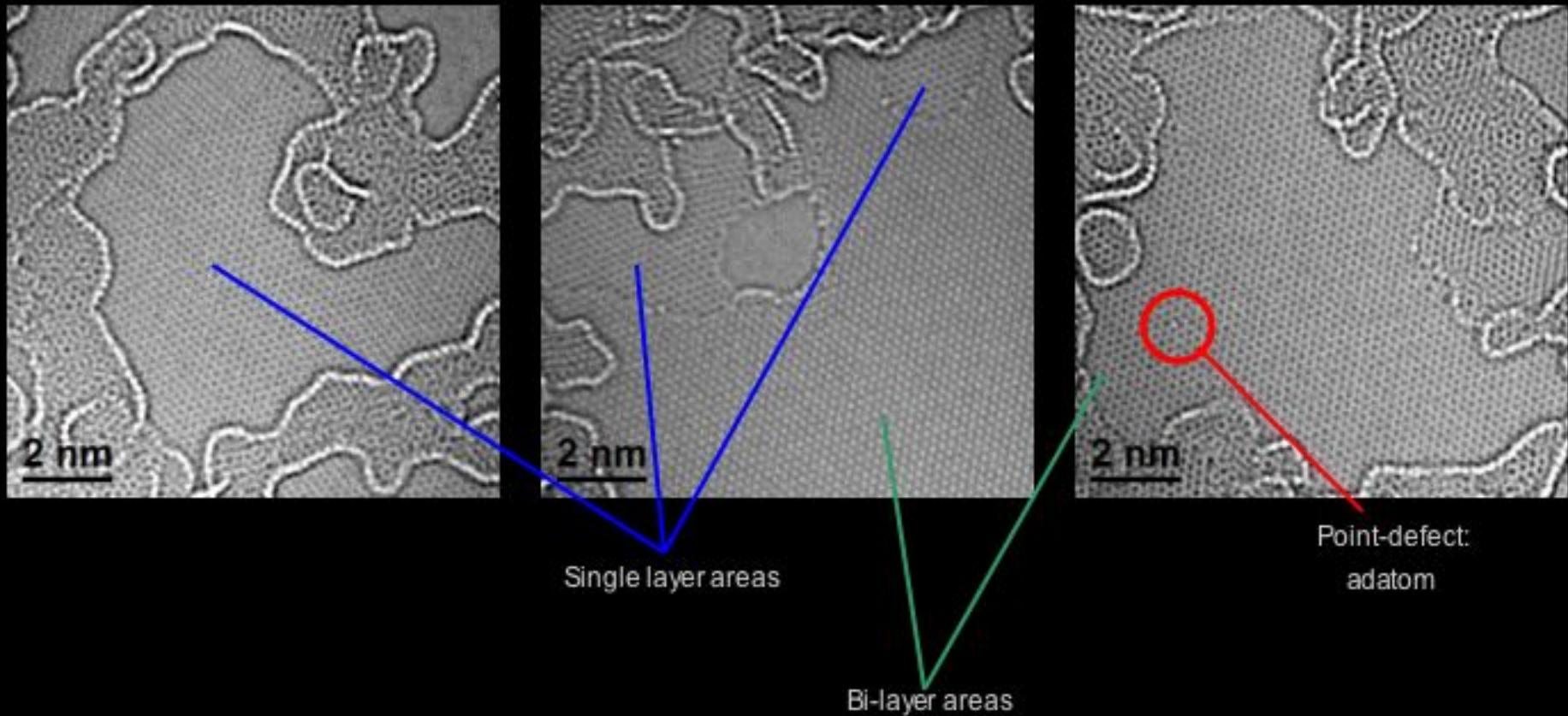


STEM focal series



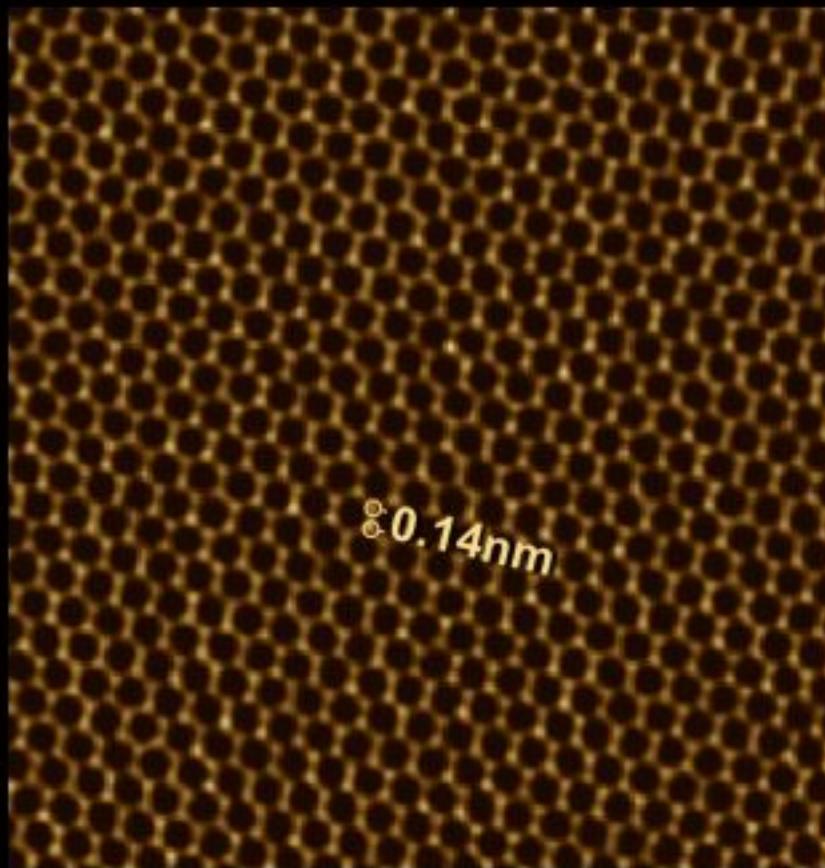
- TEAM 0.5 resolves Li atoms in core-shell precipitates in TEM mode,
 - Sensitivity to Sc, Zr and depth resolution in STEM mode.

Single and bi-layer graphene

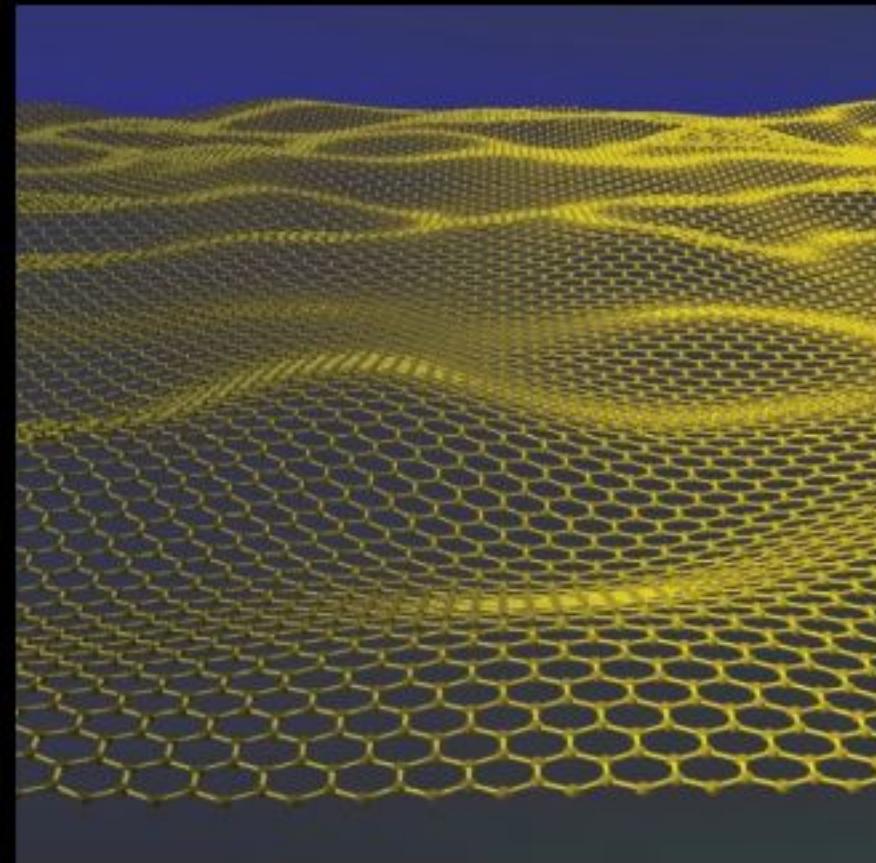


TEAM 0.5

graphene sheets



TEAM 0.5



model

80 kV, monochromator
 $C_s = -0.015 \mu\text{m}$, $C_b = 5 \text{ mm}$
Information limit < 0.1 nm

J. Meyer, R. Erni,
C. Kisielowski, 2008



Workshop Issues

N C E M

TEAM is meeting performance goals and is on track to open for user operations.

- Opportunities and scenarios for research via remote access to TEAM.
- Individual experience/interest in remote operation.
- Compatibility of remote control with different techniques of microscopy.
- Software, hardware and support requirements.
- Overview ESnet.